KAMAYA OHM

No.: MLP-K-HTS-0002 /2
Date: 2023. 1. 20

Data sheet

Title: METAL-PLATE CHIP RESISTOR; LOW OHM

Style: MLP63C

RoHS COMPLIANCE ITEM Halogen and Antimony Free

Note: •Stock conditions

Temperature: +5°C ~ +35°C Relative humidity: 25% ~ 75%

The period of guarantee: Within 2 year from shipmen t by the company.

Solderability shall be satisfied.

- Product specification contained in this data sheet are subject to change at any time without notice
- If you have any questions or a Purchasing Specification for any quality agreement is necessary, please contact our sales staff.



Hokkaido Research Center Approval by: T. Sannomiya Drawing by: M. Shibuya

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1. Scope

1.1 This data sheet covers the detail requirements for metal-plate chip resistor; low ohm, style of MLP63C.

1.2 Applicable documents

JIS C 5201-1: 2011, JIS C 5201-8: 2014, JIS C 5201-8-1: 2014 IEC60115-1: 2008, IEC60115-8: 2009, IEC60115-8-1: 2014

2. Classification

Type designation shall be the following form.

(Example)

MLP63C 6332 size, 3W

3 Temperature coefficient of resistance

Ν	±70×10 ⁻⁶ /°C
K	±100×10 ⁻⁶ / °C

4 Rated resistance

1L50	1.5mΩ
R002	2mΩ

5 Tolerance on rated resistance

F	±1%
J	±5%

6 Packaging form

TF	Embossed taping:
1 -	Embossed laping.



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3. Rating

3.1 The ratings shall be in accordance with Table-1.

Table-1

Style	Rated dissipation (W)	Rated current (A)	Temperature resistance		Rated resistance $(m\Omega)$	Tolerance on rated resistance	
	(**)		K	100	(11122)	resistarioe	
		54.7	N	±70	1		
			K	100			
		44.7	N	±70	1.5		
			K	100			
		38.7	N	±70	2		
		04.0	K	100	0.5		
		34.6	N	±70	2.5		
		21.6	K	100	3		
		31.6	N	±70	S	F(±1%) J(±5%)	
		27.3	K	100	4		
MLP63C	3.0		N	±70	7		
			K	100	5		
			N	±70	3		
		22.3	K	100	6		
		22.0	N	±70			
		20.7	K	100	7		
		20.7	N	±70	,		
		19.3	K	100	8		
			N	±70			
		18.2	K	100	9		
			N	±70	-		
		17.3	K	100	10		
				N	±70	Ĭ	!

Style	Insulation voltage (V)	Category temperature range (°C)
MLP63C 100		<i>–</i> 55~+170

3.2 Climatic category

55/170/56 Lower category temperature -55 °C

+170 °C Upper category temperature Duration of the damp heat, steady state test 56days

3.3 Stability class

5% Limits for change of resistance:

> -for long-term tests ±5% -for short-term tests ±1%

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3.4 Derating

The derated values of dissipation at temperature in excess of 70 °C shall be as indicated by the following curve.

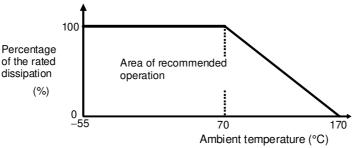


Figure-1 Derating curve

3.5 Rated voltage

d.c. or a.c. r.m.s. voltage calculated from the square root of the product of the rated resistance and the rated dissipation.

$$E = \sqrt{P \cdot R}$$

E: Rated voltage (V)

P: Rated dissipation (W)

R: Rated resistance (Ω)

3.6 Rated current

The rated current calculated from the square root of the quotient of the rated resistance and the rated dissipation.

$$I = \sqrt{P / R}$$

I: Rated current (A)

P: Rated dissipation (W)

R: Rated resistance (Ω)

The rated current shall be corresponding to rated voltage.

4. Packaging form

The standard packaging form shall be in accordance with Table-2.

Table_2

	1000 2						
Symbol	Pa	ckaging form	Standard packaging quantity / units				
TE	Embossed taping	12mm width, 4mm pitches	4,000 pcs.				

Unit: mm

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5. Dimensions

5.1 The resistor shall be of the design and physical dimensions in accordance with Figure-2 and Table-3.

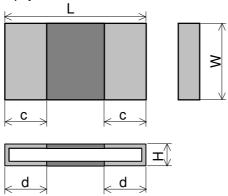


Figure-2

Table-3

Style	Rated resistance ($m\Omega$)	L	V	Н	С	d
	1	1	3.1±0.25	0.38±0.15	2.2±0.25	2.2±0.25
	1.5			0.38±0.15	1.5±0.25	1.5±0.25
	2			0.58±0.15	2.2±0.25	2.2±0.25
	2.5			0.45±0.15	2.4±0.25	2.4±0.25
	3	0.010.05		0.45±0.15	2.2±0.25	2.2±0.25
MI Deac	4			0.34±0.15	2.2±0.25	2.2±0.25
MLP63C	5	6.3±0.25		0.51±0.15	1.1±0.25	1.1±0.25
	6			0.5±0.15	1.1±0.25	1.1±0.25
	7			0.5±0.15	0.6±0.25	0.6±0.25
	8			0.35±0.15	1.1±0.25	1.1±0.25
	9			0.35±0.15	0.8±0.25	0.8±0.25
	10			0.35±0.15	0.5±0.25	0.5±0.25

5.2 Net weight (Reference)

2.2 1 4ct Weight (Helefeliee)						
Style	Rated resistance (m Ω)	Net weight (mg)				
	1					
	1.5					
	2					
	2.5					
	3					
MLP63C	4	60				
WILL GOO	5	00				
	6					
	7					
	8					
	9					
	10					



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6. Marking

The rated resistance shall be marked in 4 characters consisting of 3 figures and a letter and marked on over coat side.

 $(\text{Example}) \quad \text{``R010''} \rightarrow 0.01 \ [\Omega] \rightarrow 10 \ [\text{m}\Omega]$

"1L50" \rightarrow 0.0015 [Ω] \rightarrow 1.5 [m Ω]

7. Performance

- 7.1 The standard condition for tests shall be in accordance with Sub-clause 4.2, JIS C 5201-1: 2011.
- 7.2 The performance shall be satisfied in Table-4.

Table-4(1)

No.	Test items	Condition of test (JIS C 5201–1)					Performance requirements
1	Visual examination	Sub-clause 4.4.1 Checked by visual examination.					As in 4.4.1 The marking shall be legible, as checked by visual examination.
2	Dimension Resistance	Sub-clause 4.4.2 Resistance value shall be measured by mounting the substrate of the following condition. Current terminal Current terminal Copper clad Voltage terminal Solder resist					As specified in Table–3 of this specification. As in 4.5.2 The resistance value shall correspond with the rated resistance taking into account the specified tolerance.
					— Unit	t:mm	
		Style	Resistance value(mΩ)	а	b	С	
		MLP63C	1 to 4 1.5, 5 to 10	1.8 4.0	2.9 1.8	3.5	
		Thickness of copper clad: 0.035mm 4-Terminal method Measurement current: 1(A) Note: The measuring apparatus corresponding to DC Low-ohm Mater (1A) of AX-1152D for ADEX					
3	Voltage proof	CORPORATION. Sub-clause 4.7 Method: 4.6.1.4(See Figure–5) Test voltage: Alternating voltage with a peak value of 1.42 times the insulation voltage. Duration: 60 s±5 s				No breakdown or flash over $R{\geq}1\;G\Omega$	

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Table-4(2)

No	Test items	Condition of test (JIS C 5201–1)	Performance requirements
4	Solderability	Sub-clause 4.17 Without aging Flux: The resistors shall be immersed in a non-activated soldering flux for 2 s. Bath temperature: 235 °C±5 °C Immersion time: 2 s±0.5 s	As in 4.17.4.5 The terminations shall be covered with a smooth and bright solder coating.
5	Mounting Overload (in the mounted state) Solvent resistance of the marking	Sub-clause 4.31 Substrate material: Epoxide woven glass Test substrate: Figure–3–2 Sub-clause 4.13 The applied voltage shall be 2.5 times the rated voltage or the current corresponding to. Duration: 2 s Visual examination Resistance Sub-clause 4.30 Solvent: 2-propanol Solvent temperature: 23 °C±5 °C Method 1 Rubbing material: cotton wool Without recovery	No visible damage ΔR ≤ ±1% Legible marking
6	Mounting Bound strength of the end face plating Final measurements	Sub-clause 4.31 Substrate material: Epoxide woven glass Test substrate: Figure-4 Sub-clause 4.33 Bent value: 1 mm Resistance Sub-clause 4.33.6 Visual examination	$\Delta R \le \pm 1\%$ No visible damage

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Table-4(3)

				()	T
No	Test	item		Condition of test (JIS C 5201–1)	Performance requirements
7	Resistance heat	to	soldering	Sub-clause 4.18 (JEITA RC-2144 2.3.2) Substrate material: Epoxide woven glass Test substrate: Figure-3-1 T1:Pre-heat minimum temp.:150±5 °C T2:Pre-heat maximum temp.:180±5 °C T3:Soldering temp.:220 °C T4:Peak temp.:250 °C t1:Pre-heat duration:120±5 s t2:Soldering duration:60 to 90 s t3:Peak duration(T4-5°C):20 to 40 s Pre-reflow soldering: 1 time (Initial measurements) Reflow soldering: 3 times	
	Component resistance		solvent	Visual examination Resistance Sub-clause 4.29 Solvent: 2-propanol Solvent temperature: 23 °C±5 °C Method 2 Recovery: 48 h Visual examination Resistance	No visible damage $\Delta R \le \pm 1\%$ No visible damage $\Delta R \le \pm 1\%$
8	Mounting Adhesion			Sub-clause 4.31 Substrate material: Epoxide woven glass Test substrate: Figure-3-1 Sub-clause 4.32 Force: 5 N Duration: 10 s±1 s	
	Rapid change	e ten	nperature	Visual examination Sub-clause 4.19 Lower category temperature:-55 °C Upper category temperature:+155 °C Duration of exposure at each temperature: 30 min. Number of cycles: 5 cycles. Visual examination Resistance	No visible damage No visible damage $\Delta R \le \pm 1\%$

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Table-4(4)

No	Test items	Condition of test (JIS C 5201–1)	Performance requirements
9	Climatic sequence	Sub-clause 4.23	
	-Dry heat	Sub-clause 4.23.2	
		Test temperature: +155 °C	
		Duration: 16 h	
	-Damp heat, cycle	Sub-clause 4.23.3	
	(12+12hour cycle)	Test method: 2	
	First cycle	Test temperature: 55 °C	
	-	[Severity(2)]	
	-Cold	Sub-clause 4.23.4	
		Test temperature –55 °C	
		Duration: 2h	
	-Damp heat, cycle	Sub-clause 4.23.6	
	(12+12hour cycle)	Test method: 2	
	Remaining cycle	Test temperature: 55 °C	
		[Severity (2)]	
		Number of cycles: 5 cycles	
	-D.C. load	Sub-clause 4.23.7	
		The applied current shall be the rated current.	
		Duration: 1 min.	Nie vielkie deueen
		Visual examination	No visible damage
		Resistance	ΔR ≤ ±5 %
10	Mounting	Sub-clause 4.31	
	_	Substrate material: Epoxide woven glass	
		Test substrate: Figure-3-2	
	Endurance at 70 °C	Sub-clause 4.25.1	
		Ambient temperature: 70 °C±2 °C	
		Duration: 1000 h	
		The current shall be applied in cycles of 1.5 h on	
		and 0.5 h.	
		The applied current shall be the rated current	
		Examination at 48 h, 500 h and	
		1000 h:	
		Visual examination	No visible damage
		Resistance	ΔR ≤ ±5 %
11	Mounting	Sub-clause 4.31	
		Substrate material: Epoxide woven glass	
		Test substrate: Figure–3–1	
	Variation of resistance with	Sub-clause 4.8	As in Table–1
	temperature	+20 °C / +155 °C	



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Table-4(5)

No	Test items	Condition of test (JIS C 5201–1)	Performance requirements
12	Mounting Damp heat, steady state	Sub-clause 4.31 Substrate material: Epoxide woven glass Test substrate: Figure–3–1 Sub-clause 4.24 Ambient temperature: 40 °C±2 °C Relative humidity: 93 **2 % Without current applied. Visual examination	No visible damage
13	Dimensions (detail)	Resistance Sub-clause 4.4.3	Legible marking ΔR ≤ ±5% As in Table–4
	Mounting Endurance at upper category temperature	Sub-clause 4.31 Substrate material: Epoxide woven glass Test substrate: Figure-3-1 Sub-clause 4.25.3 Ambient temperature:170 °C±2 °C Duration: 1000 h Examination at 48 h, 500 h and 1000 h:	
		Visual examination Resistance	No visible damage ∆R ≤ ±5%

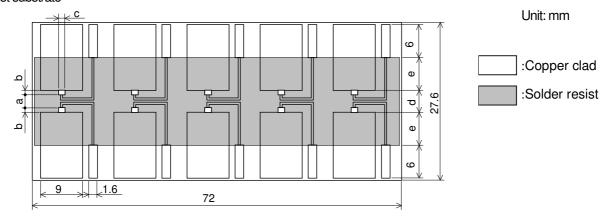
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3.5

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8. Test substrate

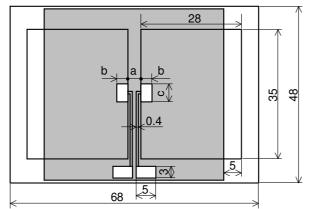


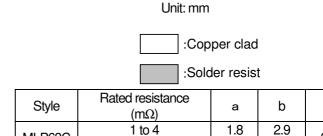
Style	Rated resistance (m Ω)	а	b	С	d	е
MLP63C	1 to 4	1.8	2.9	3.5	7.6	3.5
IVILEOSC	1.5, 5 to 10	4.0	1.8			

Figure-3-1 MLP63C TEST SUBSTRATE

Remark: Material: Epoxy resin based as glass fabric(Specified in JIS C 6484).

Thickness: 1.6mm Thickness of copper clad: 0.035mm





4.0

1.8

1.5, 5 to 10

Figure-3-2 MLP63C TEST SUBSTRATE

MLP63C

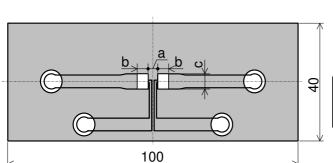
Remark: Material: Epoxy resin based as glass fabric(Specified in JIS C 6484).

Thickness: 1.6mm Thickness of copper clad: 0.07mm

However, the plating is not necessary when the connection is made by soldering.

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Unit: mm
:Copper clad
Solder resist

Style	Rated resistance (m Ω)	а	b	С
MLP63C	1 to 4	1.8	2.9	3.5
IVILFOSC	1.5, 5 to 10	4.0	1.8	

MLP63C BOUND STRENGTH OF THE END FACE PLATING TEST SUBSTRATE

Figure-4

Remark. Material: Epoxy resin based as glass fabric(Specified in JIS C 6484).

Thickness: 1.6mm Thickness of copper clad: 0.035mm

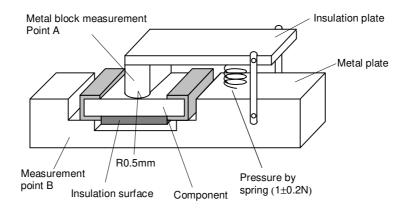


Figure-5

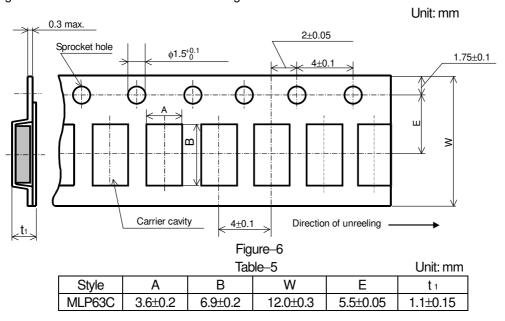
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9. Taping

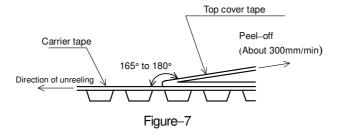
- 9.1 Applicable documents JIS C 0806-3: 2014, EIAJ ET-7200C: 2010
- 9.2 Taping dimensions
- 9.2.1 Embossed taping (12mm width, 4mm pitches)

Taping dimensions shall be in accordance with Figure-6 and Table-5.



- 1). The cover tapes shall not cover the sprocket holes.
- 2). Tapes in adjacent layers shall not stick together in the packing.
- 3). Components shall not stick to the carrier tape or to the cover tape.
- 4). Pitch tolerance over any 10 pitches ±0.2mm.
- 5). The peel strength of the top cover tape shall be with in 0.1N to 0.5N on the test method as shown in the following Figure–7.
- 6). When the tape is bent with the minimum radius for 30mm, the tape shall not be damaged and the components shall maintain their position and orientation in the tape.
- 7). In no case shall there be two or more consecutive components missing.

The maximum number of missing components shall be one or 0.1%, whichever is greater.

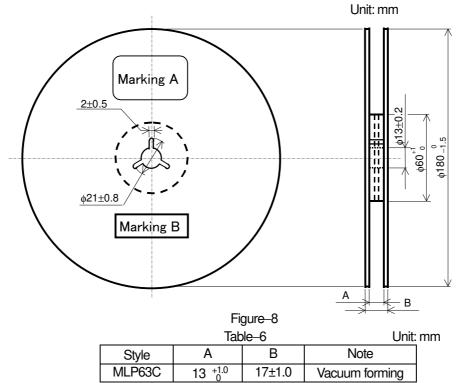


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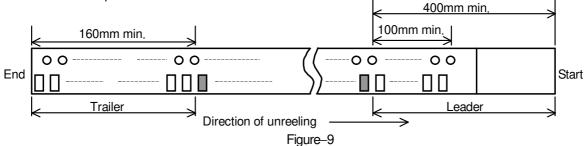
9.3 Reel dimension

Reel dimensions shall be in accordance with the following Figure–8 and Table–6. Plastic reel (Based on EIAJ ET–7200C)



Note: Marking label shall be marked on a place of Marking A or two place of Marking A and B.

9.4 Leader and trailer tape.



10. Marking on package

The label of a minimum package shall be legibly marked with follows.

10.1 Marking A

(1) Classification

(Style, Temperature coefficient of resistance, Rated resistance, Tolerance on rated resistance, Packaging form)

(2) Lot number (3) Quantity (4) Manufacturer's name or trade mark (5) Others

10.2 Marking B (KAMAYA Control label)